

Device Modeling Report

COMPONENTS: Silicon Carbide Schottky Diode
PART NUMBER: CSD20060D
MANUFACTURER: Cree, Inc.
REMARK: Professional Model

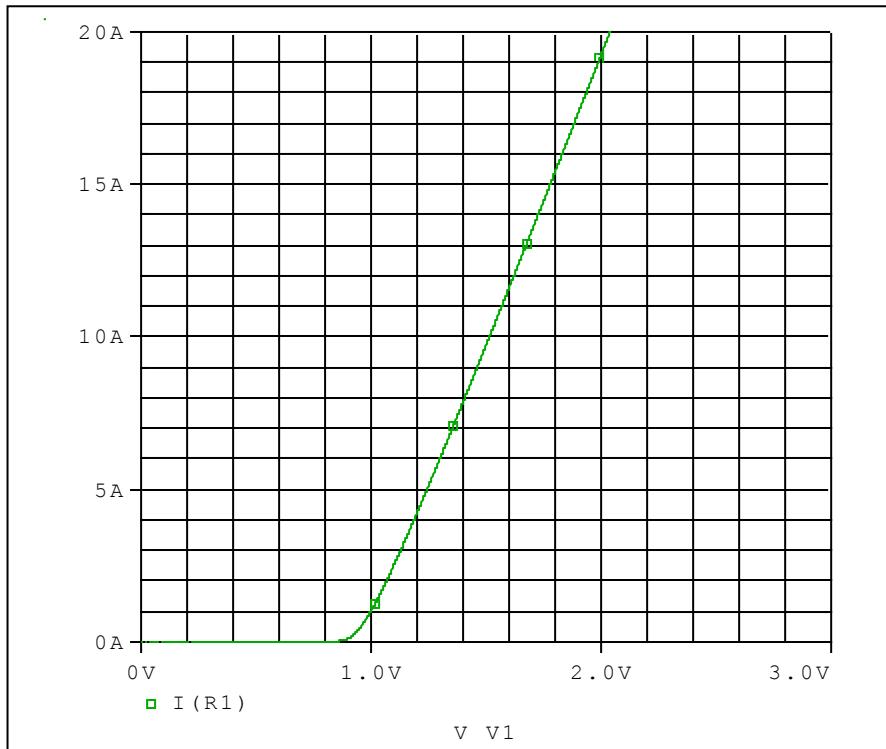


Bee Technologies Inc.

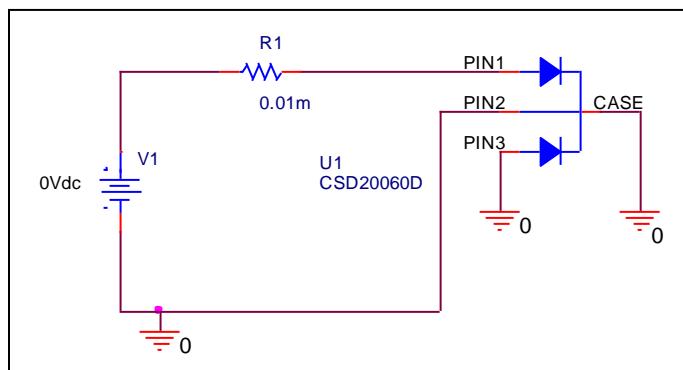
| PSpice model parameter | Model description |
|------------------------|---|
| IS | Saturation Current |
| N | Emission Coefficient |
| RS | Series Resistance |
| IKF | High-injection Knee Current |
| CJO | Zero-bias Junction Capacitance |
| M | Junction Grading Coefficient |
| VJ | Junction Potential |
| ISR | Recombination Current Saturation Value |
| BV | Reverse Breakdown Voltage(a positive value) |
| IBV | Reverse Breakdown Current(a positive value) |
| TT | Transit Time |
| EG | Energy-band Gap |

Forward Current Characteristic

Circuit Simulation Result

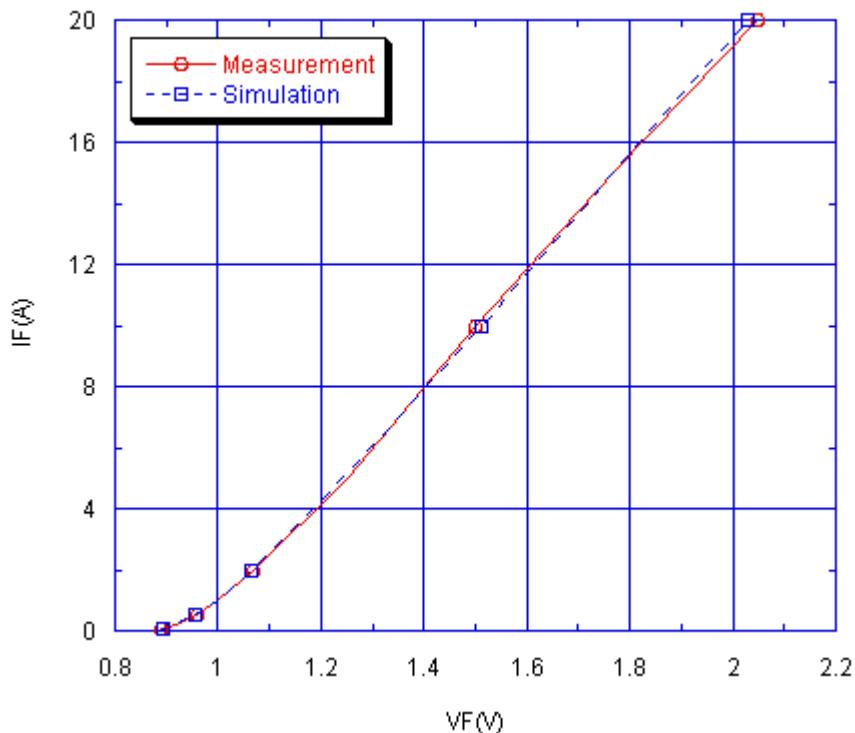


Evaluation Circuit



Comparison Graph

Circuit Simulation Result

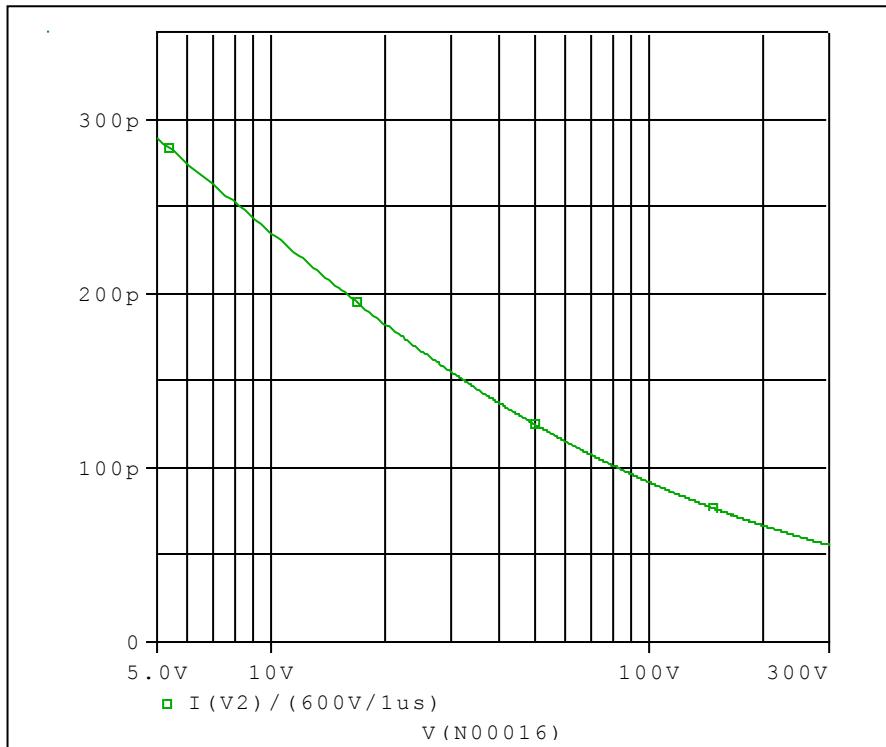


Simulation Result

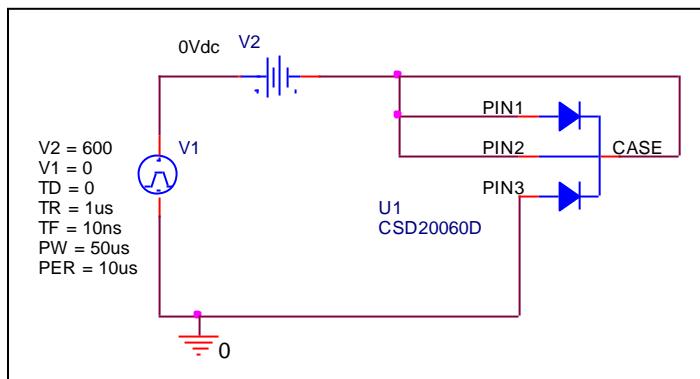
| $I_F(A)$ | $V_F(V)$ | | Error(%) |
|----------|-------------|------------|----------|
| | Measurement | Simulation | |
| 0.1 | 0.890 | 0.893 | 0.336 |
| 0.2 | 0.915 | 0.916 | 0.109 |
| 0.5 | 0.960 | 0.955 | -0.524 |
| 1 | 1.000 | 1.000 | 0.000 |
| 2 | 1.070 | 1.066 | -0.375 |
| 5 | 1.250 | 1.240 | -0.806 |
| 10 | 1.500 | 1.510 | 0.662 |
| 20 | 2.050 | 2.030 | -0.985 |

Junction Capacitance Characteristic

Circuit Simulation Result

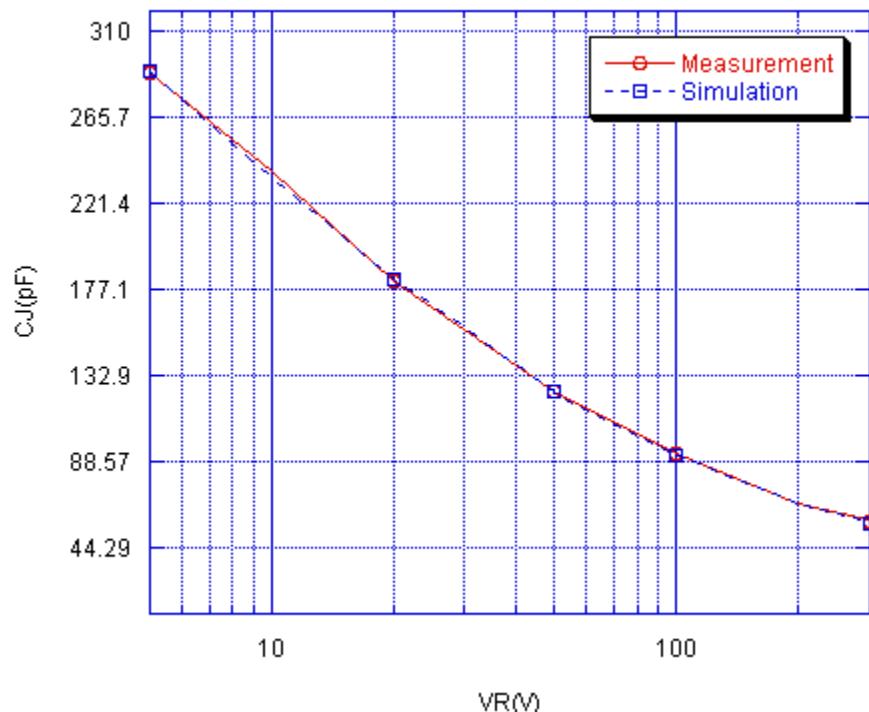


Evaluation Circuit



Comparison Graph

Circuit Simulation Result

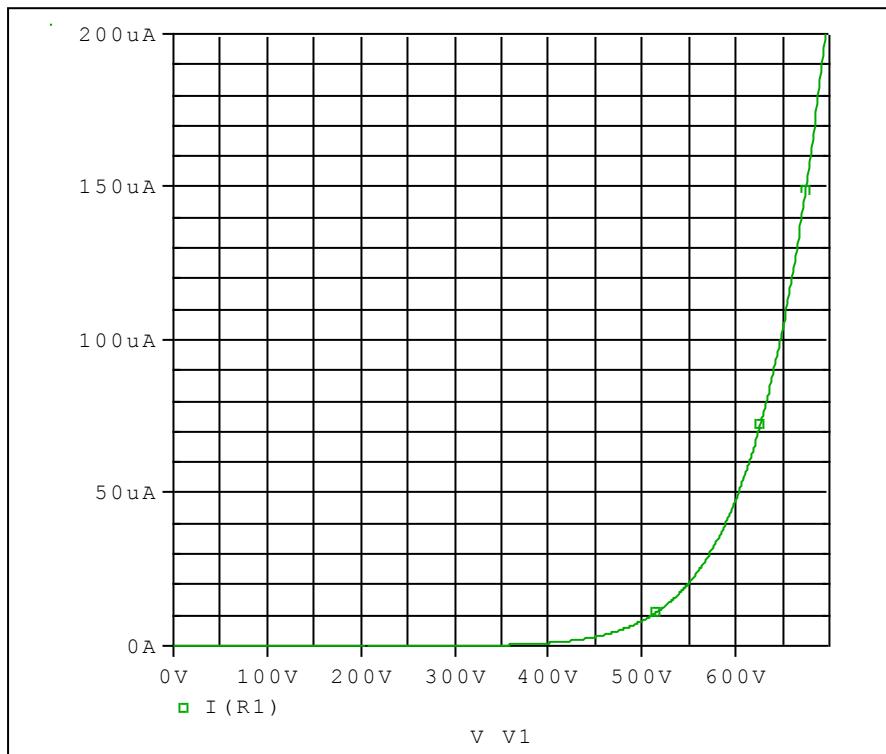


Simulation Result

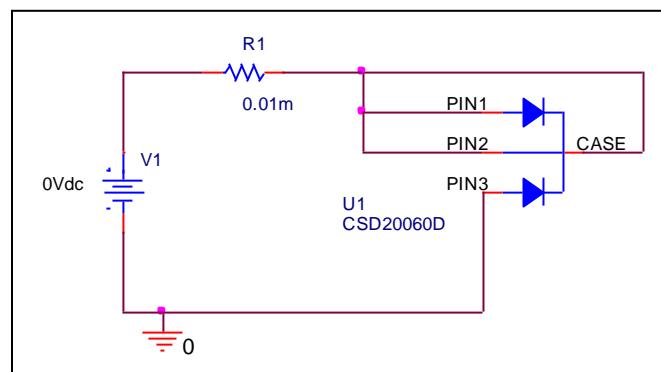
| V _R (V) | C _j (pF) | | Error(%) |
|--------------------|---------------------|------------|----------|
| | Measurement | Simulation | |
| 5 | 288.000 | 289.000 | 0.346 |
| 10 | 238.000 | 235.000 | -1.277 |
| 20 | 181.000 | 182.000 | 0.549 |
| 50 | 124.000 | 123.888 | -0.090 |
| 100 | 92.000 | 91.500 | -0.546 |
| 200 | 67.000 | 67.000 | 0.000 |
| 300 | 57.000 | 56.000 | -1.786 |

Reverse Characteristic

Circuit Simulation Result

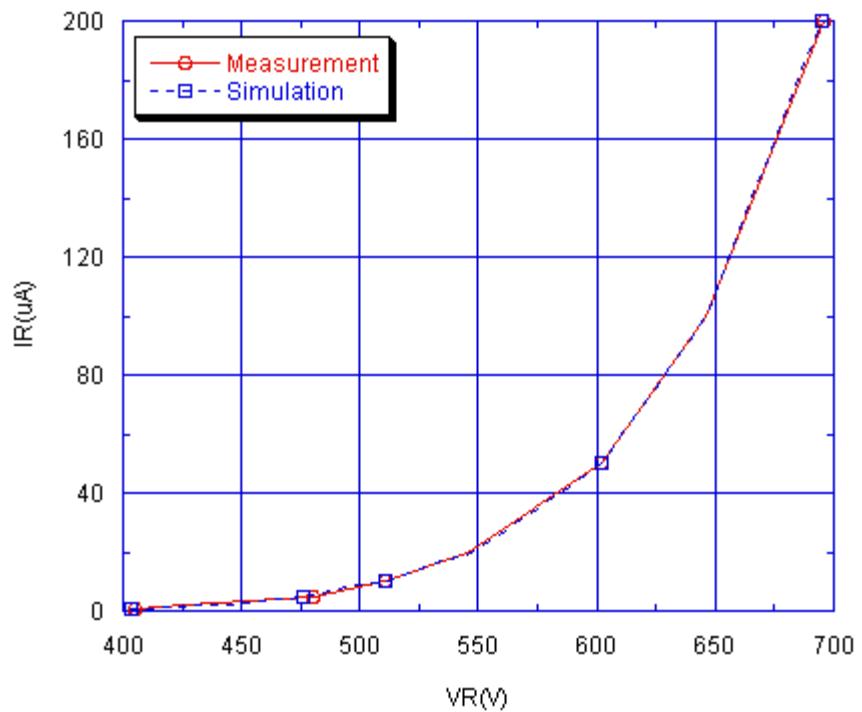


Evaluation Circuit



Comparison Graph

Circuit Simulation Result



Simulation Result

| I_R (μA) | V_R (V) | | Error(%) |
|-------------------------|-------------|------------|----------|
| | Measurement | Simulation | |
| 1 | 405.000 | 403.000 | -0.496 |
| 2 | 426.000 | 430.000 | 0.930 |
| 5 | 480.000 | 476.000 | -0.840 |
| 10 | 511.000 | 510.000 | -0.196 |
| 20 | 545.000 | 547.000 | 0.366 |
| 50 | 602.000 | 601.584 | -0.069 |
| 100 | 646.000 | 645.844 | -0.024 |
| 200 | 696.000 | 695.000 | -0.144 |